

GENERAL DESCRIPTION

The 87608I has a selectable REF_CLK or crystal input. The REF_CLK input accepts LVCMOS or LVTTTL input levels. The 87608I has a fully integrated PLL along with frequency configurable clock and feedback outputs for multiplying and regenerating clocks with “zero delay”.

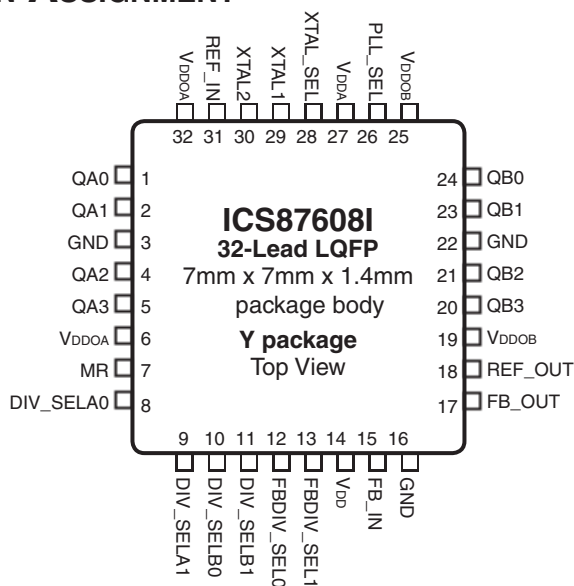
The 87608I is a 1:8 PCI/PCI-X Clock Generator. The 87608I has a selectable REF_CLK or crystal input. The REF_CLK input accepts LVCMOS or LVTTTL input levels. The 87608I has a fully integrated PLL along with frequency configurable clock and feedback outputs for multiplying and regenerating clocks with “zero delay”. The PLL’s VCO has an operating range of 250MHz-500MHz, allowing this device to be used in a variety of general purpose clocking applications. For PCI/PCI-X applications in particular, the VCO frequency should be set to 400MHz. This can be accomplished by supplying 33.33MHz, 25MHz, 20MHz, or 16.66MHz on the reference clock or crystal input and by selecting ÷12, ÷16, ÷20, or ÷24, respectively as the feedback divide value. The dividers on each of the two output banks can then be independently configured to generate 33.33MHz (÷12), 66.66MHz (÷6), 100MHz (÷4), or 133.33MHz (÷3).

The 87608I is characterized to operate with its core supply at 3.3V and each bank supply at 3.3V or 2.5V. The 87608I is packaged in a small 7x7mm body LQFP, making it ideal for use in space-constrained applications.

FEATURES

- Fully integrated PLL
- Eight LVCMOS/LVTTTL outputs, 15Ω typical output impedance
- Selectable crystal oscillator interface or LVCMOS/LVTTTL REF_IN clock input
- Maximum output frequency: 166.67MHz
- Maximum crystal input frequency: 38MHz
- Maximum REF_IN input frequency: 41.67MHz
- Individual banks with selectable output dividers for generating 33.333MHz, 66.66MHz, 100MHz and 133.333MHz
- Separate feedback control for generating PCI / PCI-X frequencies from a 16.66MHz or 20MHz crystal, or 25MHz or 33.33MHz reference frequency
- VCO range: 200MHz to 500MHz
- Cycle-to-cycle jitter: 120ps (maximum), @ 3.3V
- Period jitter, RMS: 20ps (maximum)
- Output skew: 250ps (maximum)
- Bank skew: 60ps (maximum)
- Static phase offset: 160ps ± 160ps
- Voltage Supply Modes:
 V_{DD} (core/inputs), V_{DDA} (analog supply for PLL),
 V_{DDOA} (output bank A),
 V_{DDOB} (output bank B, REF_OUT, FB_OUT)
 $V_{DD}/V_{DDA}/V_{DDOA}/V_{DDOB}$
 3.3/3.3/3.3/3.3
 3.3/3.3/2.5/3.3
 3.3/3.3/3.3/2.5
 3.3/3.3/2.5/2.5
- -40°C to 85°C ambient operating temperature
- Available in lead-free RoHS compliant package

PIN ASSIGNMENT



BLOCK DIAGRAM

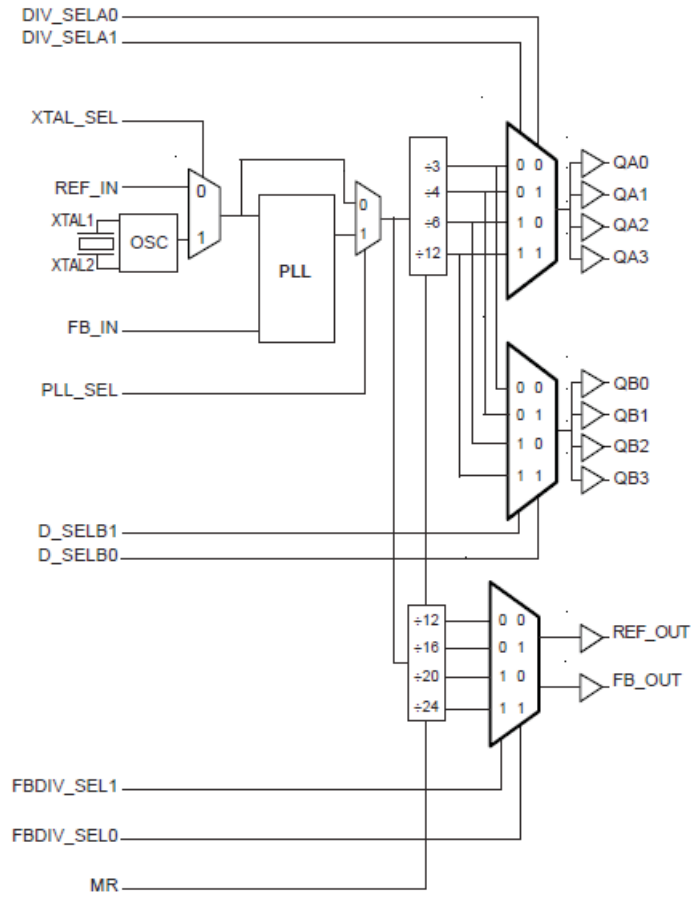


TABLE 1. PIN DESCRIPTIONS

| Number | Name | Type | | Description |
|----------------|--|--------|----------|---|
| 1, 2, 4, 5 | QA0, QA1, QA2, QA3 | Output | | Bank A clock outputs. 15Ω typical output impedance. LVCMOS / LVTTTL interface levels. |
| 3, 16, 22 | GND | Power | | Power supply ground. |
| 6, 32 | V _{DDOA} | Power | | Output supply pins for Bank A outputs. |
| 7 | MR | Input | Pulldown | Active HIGH Master Reset. When logic HIGH, the internal dividers are reset causing the outputs go low. When logic LOW, the internal dividers and the outputs are enabled. LVCMOS / LVTTTL interface levels. |
| 8, 9, 10, 11 | DIV_SELA0, DIV_SELA1, DIV_SELB0, DIV_SELB1 | Input | Pulldown | Selects divide value for clock outputs as described in Table 3. LVCMOS / LVTTTL interface levels. |
| 12, 13 | FBDIV_SEL0, FBDIV_SEL1 | Input | Pulldown | Selects divide value for reference clock output and feedback output. LVCMOS / LVTTTL interface levels. |
| 14 | V _{DD} | Power | | Core supply pin. |
| 15 | FB_IN | Input | Pulldown | Feedback input to phase detector for generating clocks with “zero delay”. LVCMOS / LVTTTL interface levels. |
| 17 | FB_OUT | Output | | Feedback output. Connect to FB_IN. LVCMOS / LVTTTL interface levels. |
| 18 | REF_OUT | Output | | Reference clock output. LVCMOS / LVTTTL interface levels. |
| 19, 25 | V _{DDOB} | Power | | Output supply pins for Bank B and REF_OUT, FB_OUT outputs. |
| 20, 21, 23, 24 | QB3, QB2, QB1, QB0 | Output | | Bank B clock outputs. 15Ω typical output impedance. LVCMOS / LVTTTL interface levels. |
| 26 | PLL_SEL | Input | Pullup | Selects between PLL and bypass mode. When HIGH, selects PLL. When LOW, selects reference clock. LVCMOS / LVTTTL interface levels. |
| 27 | V _{DDA} | Power | | Analog supply pin. See Applications Note for filtering. |
| 28 | XTAL_SEL | Input | Pullup | Selects between crystal oscillator or reference clock as the PLL reference source. Selects XTAL inputs when HIGH. Selects REF_IN when LOW. LVCMOS / LVTTTL interface levels. |
| 29, 30 | XTAL1, XTAL2 | Input | | Crystal oscillator interface. XTAL1 is the input. XTAL2 is the output. |
| 31 | REF_IN | Input | Pulldown | Reference clock input. LVCMOS / LVTTTL interface levels. |

NOTE: *Pullup* and *Pulldown* refer to internal input resistors. See Table 2, Pin Characteristics, for typical values.

TABLE 2. PIN CHARACTERISTICS

| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|-----------------------|--|---|---------|---------|---------|-------|
| C _{IN} | Input Capacitance | | | 4 | | pF |
| R _{PULLUP} | Input Pullup Resistor | | | 51 | | kΩ |
| R _{PULLDOWN} | Input Pulldown Resistor | | | 51 | | kΩ |
| C _{PD} | Power Dissipation Capacitance (per output); NOTE 1 | V _{DD} , V _{DDA} , V _{DDOX} = 3.465V | | | 9 | pF |
| | | V _{DD} , V _{DDA} = 3.465V; V _{DDOX} = 2.625V | | | 11 | pF |
| R _{OUT} | Output Impedance | | | 15 | | Ω |

V_{DDOX} denotes V_{DDOA} and V_{DDOB}.

TABLE 3A. OUTPUT CONTROL PIN FUNCTION TABLE

| Inputs | | Outputs | |
|--------|---------|--------------------------|--|
| MR | QA0:QA3 | QB0:QB3, FB_OUT, REF_OUT | |
| 1 | LOW | LOW | |
| 0 | Active | Active | |

TABLE 3B. OPERATING MODE FUNCTION TABLE

| Inputs | | Operating Mode |
|---------|--|----------------|
| PLL_SEL | | |
| 0 | | Bypass |
| 1 | | PLL |

TABLE 3C. PLL INPUT FUNCTION TABLE

| Inputs | |
|----------|-----------------|
| XTAL_SEL | PLL Input |
| 0 | REF_IN |
| 1 | XTAL Oscillator |

TABLE 3D. CONTROL FUNCTION TABLE

| Inputs | | | | | | | Outputs | | |
|------------|------------|------------------|------------------|------------------|------------------|---------------------------------|------------|----------------|---------------|
| FBDIV_SEL1 | FBDIV_SEL0 | Bank B DIV_SELB1 | Bank B DIV_SELB0 | Bank A DIV_SELA1 | Bank A DIV_SELA0 | Reference Frequency Range (MHz) | PLL_SEL =1 | Frequency | |
| | | | | | | | QX0:QX3 | QX0:QX3 (MHz) | FB_OUT (MHz) |
| 0 | 0 | 0 | 0 | 0 | 0 | 16.67 - 41.67 | x 4 | 66.68 - 166.68 | 16.67 - 41.67 |
| 0 | 0 | 0 | 1 | 0 | 1 | 16.67 - 41.67 | x 3 | 50 - 125 | 16.67 - 41.67 |
| 0 | 0 | 1 | 0 | 1 | 0 | 16.67 - 41.67 | x 2 | 33.34 - 83.34 | 16.67 - 41.67 |
| 0 | 0 | 1 | 1 | 1 | 1 | 16.67 - 41.67 | x 1 | 16.67 - 41.67 | 16.67 - 41.67 |
| 0 | 1 | 0 | 0 | 0 | 0 | 12.5 - 31.25 | x 5.33 | 66.63 - 166.56 | 12.5 - 31.25 |
| 0 | 1 | 0 | 1 | 0 | 1 | 12.5 - 31.25 | x 4 | 50 - 125 | 12.5 - 31.25 |
| 0 | 1 | 1 | 0 | 1 | 0 | 12.5 - 31.25 | x 2.667 | 33.34 - 83.34 | 12.5 - 31.25 |
| 0 | 1 | 1 | 1 | 1 | 1 | 12.5 - 31.25 | x 1.33 | 16.63 - 41.56 | 12.5 - 31.25 |
| 1 | 0 | 0 | 0 | 0 | 0 | 10 - 25 | x 6.667 | 66.67 - 166.68 | 10 - 25 |
| 1 | 0 | 0 | 1 | 0 | 1 | 10 - 25 | x 5 | 50 - 125 | 10 - 25 |
| 1 | 0 | 1 | 0 | 1 | 0 | 10 - 25 | x 3.33 | 33.30 - 83.25 | 10 - 25 |
| 1 | 0 | 1 | 1 | 1 | 1 | 10 - 25 | x 1.66 | 16.60 - 41.50 | 10 - 25 |
| 1 | 1 | 0 | 0 | 0 | 0 | 8.33 - 20.83 | x 8 | 66.64 - 166.64 | 8.33 - 20.83 |
| 1 | 1 | 0 | 1 | 0 | 1 | 8.33 - 20.83 | x 6 | 50 - 125 | 8.33 - 20.83 |
| 1 | 1 | 1 | 0 | 1 | 0 | 8.33 - 20.83 | x 4 | 33.32 - 83.32 | 8.33 - 20.83 |
| 1 | 1 | 1 | 1 | 1 | 1 | 8.33 - 20.83 | x 2 | 16.66 - 41.66 | 8.33 - 20.83 |

NOTE: VCO frequency range for all configurations above is 200MHz to 500MHz.

ABSOLUTE MAXIMUM RATINGS

| | |
|--|---------------------------|
| Supply Voltage, V_{DD} | 4.6V |
| Inputs, V_I | -0.5V to $V_{DD} + 0.5V$ |
| Outputs, V_O | -0.5V to $V_{DDO} + 0.5V$ |
| Package Thermal Impedance, θ_{JA} | 47.9°C/W (0 lfp/m) |
| Storage Temperature, T_{STG} | -65°C to 150°C |

NOTE: Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics* or *AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

TABLE 4A. POWER SUPPLY DC CHARACTERISTICS, $V_{DD} = V_{DDA} = 3.3V \pm 5\%$, $V_{DDOX} = 3.3V \pm 5\%$ OR $2.5V \pm 5\%$, $T_A = -40^\circ\text{C}$ TO 85°C

| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|------------|-----------------------|-----------------|---------|---------|---------|-------|
| V_{DD} | Core Supply Voltage | | 3.135 | 3.3 | 3.465 | V |
| V_{DDA} | Analog Supply Voltage | | 3.135 | 3.3 | 3.465 | V |
| V_{DDOX} | Output Supply Voltage | | 3.135 | 3.3 | 3.465 | V |
| I_{DD} | Power Supply Current | | | | 185 | mA |
| I_{DDA} | Analog Supply Current | | | | 15 | mA |
| I_{DDOA} | Output Supply Current | | | | 20 | mA |
| I_{DDOB} | Output Supply Current | | | | 20 | mA |

V_{DDOX} denotes V_{DDOA} , V_{DDOB} .

TABLE 4B. LVCMOS/LVTTL DC CHARACTERISTICS, $V_{DD} = V_{DDA} = 3.3V \pm 5\%$, $V_{DDOX} = 3.3V \pm 5\%$ OR $2.5V \pm 5\%$, $T_A = -40^\circ\text{C}$ TO 85°C

| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|----------|-----------------------------|--|--------------------------------------|---------|----------------|---------------|
| V_{IH} | Input High Voltage | MR, DIV_SELx0, DIV_SELx1, FB-DIV_SEL0, FB-DIV_SEL1, XTAL_SEL, FB_IN, PLL_SEL | 2 | | $V_{DD} + 0.3$ | V |
| | | REF_IN | 2 | | $V_{DD} + 0.3$ | V |
| V_{IL} | Input Low Voltage | MR, DIV_SELx0, DIV_SELx1, FB-DIV_SEL0, FB-DIV_SEL1, XTAL_SEL, FB_IN, PLL_SEL | -0.3 | | 0.8 | V |
| | | REF_IN | -0.3 | | 1.3 | V |
| I_{IH} | Input High Current | DIV_SELx0, DIV_SELx1, FB-DIV_SEL0, FB-DIV_SEL1, MR, FB_IN | $V_{DD} = V_{IN} = 3.465V$ | | 150 | μA |
| | | XTAL_SEL, PLL_SEL | $V_{DD} = V_{IN} = 3.465V$ | | 5 | μA |
| I_{IL} | Input Low Current | DIV_SELx0, DIV_SELx1, FB-DIV_SEL0, FB-DIV_SEL1, MR, FB_IN | $V_{DD} = 3.465V$, $V_{IN} = 0V$ | -5 | | μA |
| | | XTAL_SEL, PLL_SEL | $V_{DD} = 3.465V$, $V_{IN} = 0V$ | -150 | | μA |
| V_{OH} | Output High Voltage; NOTE 1 | $V_{DD} = V_{IN} = 3.465V$ | 2.6 | | | V |
| | | $V_{DD} = V_{IN} = 2.625V$ | 1.8 | | | V |
| V_{OL} | Output Low Voltage; NOTE 1 | | | | 0.5 | V |

NOTE 1: Outputs terminated with 50Ω to $V_{DDOX}/2$. See Parameter Measurement Information section, "3.3V Output Load Test Circuit".

TABLE 5. CRYSTAL CHARACTERISTICS

| Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|------------------------------------|-----------------|-------------|---------|---------|----------|
| Mode of Oscillation | | Fundamental | | | |
| Frequency | | 10 | | 38 | MHz |
| Equivalent Series Resistance (ESR) | | | | 50 | Ω |
| Shunt Capacitance | | | 7 | | pF |
| Drive Level | | | | 1 | mW |

TABLE 6. PLL INPUT REFERENCE CHARACTERISTICS, $V_{DD} = V_{DDA} = V_{DDOX} = 3.3V \pm 5\%$, $T_A = -40^\circ\text{C}$ TO 85°C

| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|-----------|---------------------|-----------------|---------|---------|---------|-------|
| f_{REF} | Reference Frequency | | 8.33 | | 41.67 | MHz |

TABLE 7A. AC CHARACTERISTICS, $V_{DD} = V_{DDA} = V_{DDOX} = 3.3V \pm 5\%$, $T_A = -40^\circ\text{C}$ TO 85°C

| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|----------------|----------------------------------|--------------------------|---------|---------|---------|-------|
| f_{MAX} | Output Frequency | | | | 166.67 | MHz |
| $t(\emptyset)$ | Static Phase Offset; NOTE 1 | $F_{REF} = 25\text{MHz}$ | 0 | 160 | 325 | ps |
| $t_{sk}(b)$ | Bank Skew; NOTE 2, 6 | | | | 60 | ps |
| $t_{sk}(o)$ | Output Skew; NOTE 3, 6 | | | | 250 | ps |
| $t_{jit}(cc)$ | Cycle-to-Cycle Jitter; 6 | | | | 120 | ps |
| $t_{jit}(per)$ | Period Jitter, RMS; NOTE 4, 6, 7 | | | | 20 | ps |
| $t_{sl}(o)$ | Slew Rate | | 1 | | 4 | v/ns |
| t_L | PLL Lock Time | | | | 10 | ms |
| t_R / t_F | Output Rise/Fall Time | 20% to 80% | 200 | | 700 | ps |
| odc | Output Duty Cycle; NOTE 5 | | 48 | | 52 | % |

All parameters measured with feedback and output dividers set to DIV by 12 unless otherwise noted.

NOTE 1: Defined as the time difference between the input reference clock and the average feedback input signal when the PLL is locked and the input reference frequency is stable. Measured at $V_{DD}/2$.

NOTE 2: Defined as skew within a bank of outputs at the same voltages and with equal load conditions.

NOTE 3: Defined as skew between outputs at the same supply voltage and with equal load conditions.

Measured at $V_{DDOX}/2$.

NOTE 4: Jitter performance using LVCMOS inputs.

NOTE 5: Measured using REF_IN. For XTAL input, refer to Application Note.

NOTE 6: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 7: This parameter is defined as an RMS value.

TABLE 7B. AC CHARACTERISTICS, $V_{DD} = V_{DDA} = 3.3V \pm 5\%$, $V_{DDOX} = 2.5V \pm 5\%$, $T_A = -40^\circ\text{C}$ TO 85°C

| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|----------------|----------------------------------|-----------------|---------|---------|---------|-------|
| f_{MAX} | Output Frequency | | | | 166.67 | MHz |
| $t(\emptyset)$ | Static Phase Offset; NOTE 1 | FREF = 25MHz | -365 | -105 | 160 | ps |
| $t_{sk}(b)$ | Bank Skew; NOTE 2, 6 | | | | 60 | ps |
| $t_{sk}(o)$ | Output Skew; NOTE 3, 6 | | | | 250 | ps |
| $t_{jit}(cc)$ | Cycle-to-Cycle Jitter; 6 | | | | 170 | ps |
| $t_{jit}(per)$ | Period Jitter, RMS; NOTE 4, 6, 7 | | | | 20 | ps |
| $t_{sl}(o)$ | Slew Rate | | 1 | | 4 | v/ns |
| t_L | PLL Lock Time | | | | 10 | ms |
| t_R / t_F | Output Rise/Fall Time | 20% to 80% | 200 | | 700 | ps |
| odc | Output Duty Cycle; NOTE 5 | | 48 | | 52 | % |

All parameters measured with feedback and output dividers set to DIV by 12 unless otherwise noted.

NOTE 1: Defined as the time difference between the input reference clock and the average feedback input signal when the PLL is locked and the input reference frequency is stable. Measured at $V_{DD}/2$.

NOTE 2: Defined as skew within a bank of outputs at the same voltages and with equal load conditions.

NOTE 3: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at $V_{DDOX}/2$.

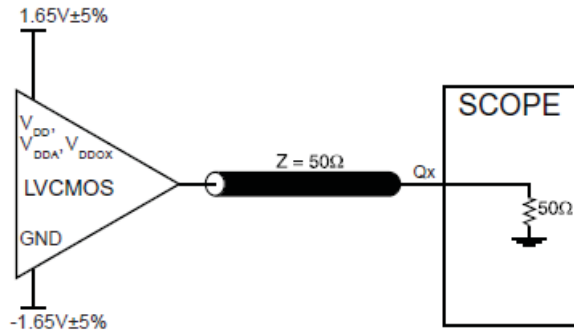
NOTE 4: Jitter performance using LVCMOS inputs.

NOTE 5: Measured using REF_IN. For XTAL input, refer to Application Note.

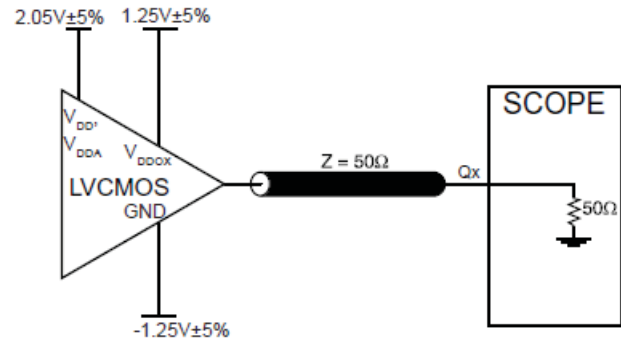
NOTE 6: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 7: This parameter is defined as an RMS value.

PARAMETER MEASUREMENT INFORMATION



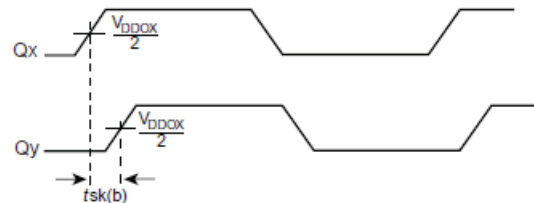
3.3V OUTPUT LOAD AC TEST CIRCUIT
(Where X denotes outputs in the same Bank)



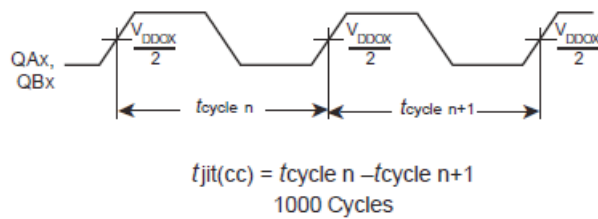
3.3V/2.5V OUTPUT LOAD AC TEST CIRCUIT



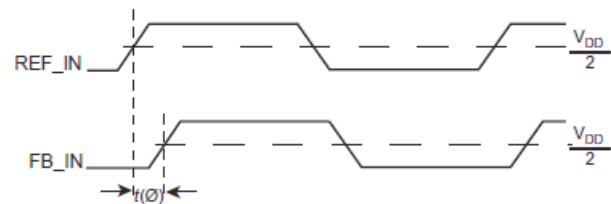
OUTPUT SKEW



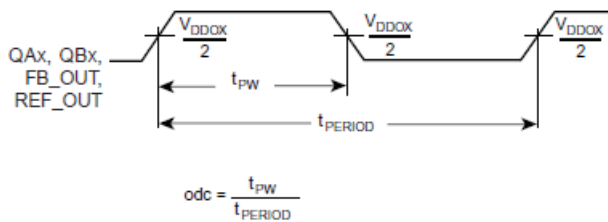
BANK SKEW



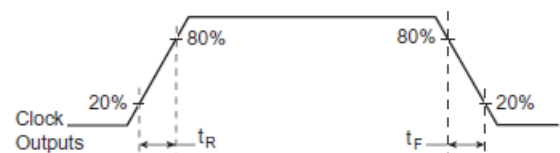
CYCLE-TO-CYCLE JITTER



STATIC PHASE OFFSET



OUTPUT PULSE WIDTH/PULSE WIDTH PERIOD



OUTPUT RISE/FALL TIME

APPLICATION INFORMATION

POWER SUPPLY FILTERING TECHNIQUES

As in any high speed analog circuitry, the power supply pins are vulnerable to random noise. The 87608I provides separate power supplies to isolate any high switching noise from the outputs to the internal PLL. V_{DD} , V_{DDA} , and V_{DDOX} should be individually connected to the power supply plane through vias, and bypass capacitors should be used for each pin. To achieve optimum jitter performance, power supply isolation is required. *Figure 1* illustrates how a 10Ω resistor along with a $10\mu\text{F}$ and a $.01\mu\text{F}$ bypass capacitor should be connected to each V_{DDA} .

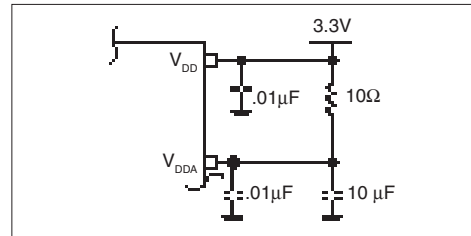


FIGURE 1. POWER SUPPLY FILTERING

RECOMMENDATIONS FOR UNUSED INPUT AND OUTPUT PINS

INPUTS:

LVC MOS CONTROL PINS:

All control pins have internal pull-ups or pull-downs; additional resistance is not required but can be added for additional protection. A $1\text{k}\Omega$ resistor can be used.

OUTPUTS:

LVC MOS OUTPUT:

All unused LVC MOS output can be left floating. We recommend that there is no trace attached.

CRYSTAL INPUT INTERFACE

The 87608I has been characterized with 18pF parallel resonant crystals. The capacitor values, C1 and C2, shown in Figure 2 below were determined using a 25MHz, 18pF parallel

resonant crystal and were chosen to minimize the frequency ppm error. The optimum C1 and C2 values can be slightly adjusted for optimum frequency accuracy.

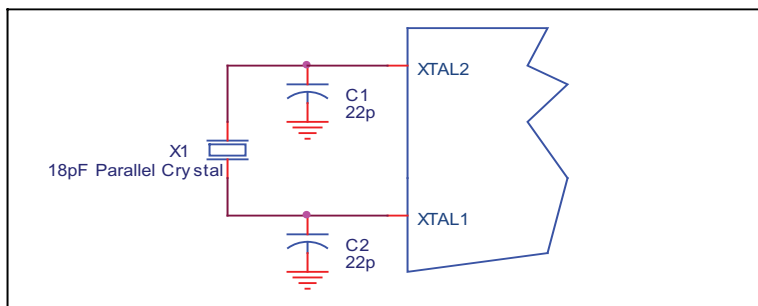


Figure 2. CRYSTAL INPUT INTERFACE

LVC MOS TO XTAL INTERFACE

The XTAL_IN input can accept a single-ended LVC MOS signal through an AC coupling capacitor. A general interface diagram is shown in Figure 3. The XTAL_OUT pin can be left floating. The input edge rate can be as slow as 10ns. For LVC MOS inputs, it is recommended that the amplitude be reduced from full swing to half swing in order to prevent signal interference with the power rail and to reduce noise. This configuration requires

that the output impedance of the driver (R_o) plus the series resistance (R_s) equals the transmission line impedance. In addition, matched termination at the crystal input will attenuate the signal in half. This can be done in one of two ways. First, R1 and R2 in parallel should equal the transmission line impedance. For most 50Ω applications, R1 and R2 can be 100Ω. This can also be accomplished by removing R1 and making R2 50Ω.

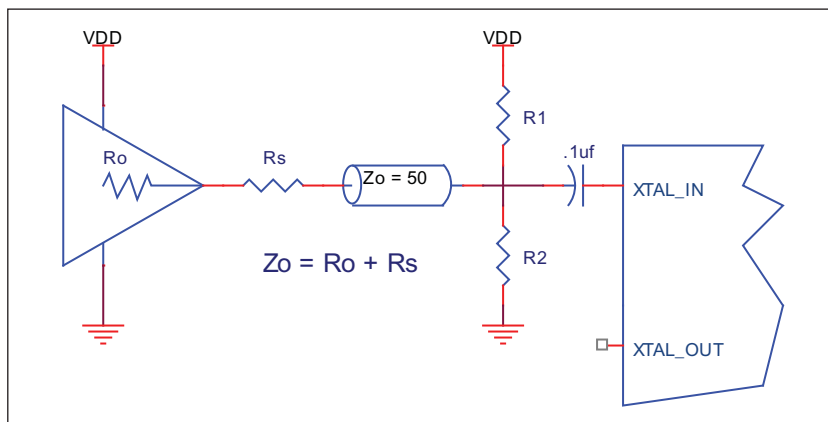


FIGURE 3. GENERAL DIAGRAM FOR LVC MOS DRIVER TO XTAL INPUT INTERFACE

RELIABILITY INFORMATION

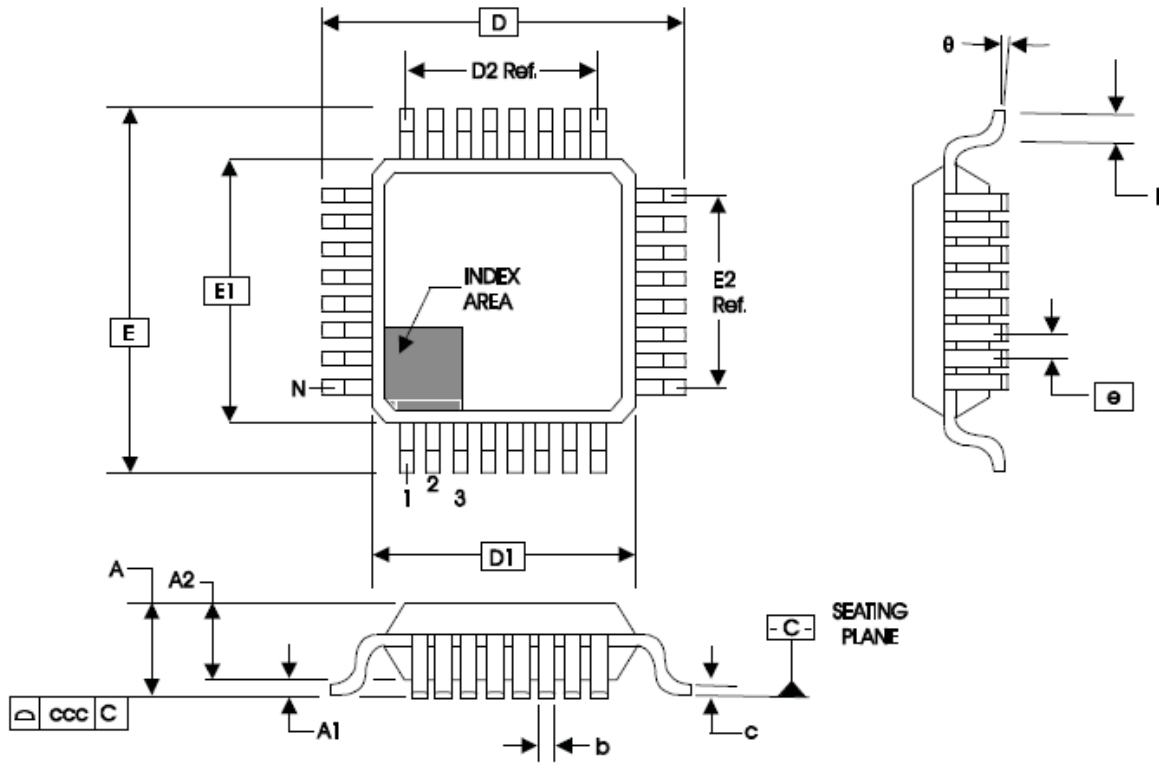
TABLE 8. θ_{JA} vs. AIR FLOW TABLE FOR 32 LEAD LQFP

| θ_{JA} by Velocity (Linear Feet per Minute) | | | |
|--|----------|------------|------------|
| | 0 | 200 | 500 |
| Single-Layer PCB, JEDEC Standard Test Boards | 67.8°C/W | 55.9°C/W | 50.1°C/W |
| Multi-Layer PCB, JEDEC Standard Test Boards | 47.9°C/W | 42.1°C/W | 39.4°C/W |

NOTE: Most modern PCB designs use multi-layered boards. The data in the second row pertains to most designs.

TRANSISTOR COUNT

The transistor count for 87608I is: 5495

PACKAGE OUTLINE - Y SUFFIX FOR 32 LEAD LQFP

TABLE 9. PACKAGE DIMENSIONS

| JEDEC VARIATION ALL DIMENSIONS IN MILLIMETERS | | | |
|--|------------|---------|---------|
| SYMBOL | BBA | | |
| | MINIMUM | NOMINAL | MAXIMUM |
| N | 32 | | |
| A | -- | -- | 1.60 |
| A1 | 0.05 | -- | 0.15 |
| A2 | 1.35 | 1.40 | 1.45 |
| b | 0.30 | 0.37 | 0.45 |
| c | 0.09 | -- | 0.20 |
| D | 9.00 BASIC | | |
| D1 | 7.00 BASIC | | |
| D2 | 5.60 Ref. | | |
| E | 9.00 BASIC | | |
| E1 | 7.00 BASIC | | |
| E2 | 5.60 Ref. | | |
| e | 0.80 BASIC | | |
| L | 0.45 | 0.60 | 0.75 |
| θ | 0° | -- | 7° |
| ccc | -- | -- | 0.10 |

Reference Document: JEDEC Publication 95, MS-026

TABLE 10. ORDERING INFORMATION

| Part/Order Number | Marking | Package | Shipping Packaging | Temperature |
|--------------------------|----------------|--------------------------|---------------------------|--------------------|
| 87608AYILF | ICS87608AILF | 32 lead "Lead Free" LQFP | Tray | -40°C to +85°C |
| 87608AYILFT | ICS87608AILF | 32 lead "Lead Free" LQFP | Tape and Reel | -40°C to +85°C |

| REVISION HISTORY SHEET | | | | |
|------------------------|-------|---------|--|----------|
| Rev | Table | Page | Description of Change | Date |
| A | | 2 | Corrected MR in the Block Diagram. | 4/6/04 |
| A | | 7 | Parameter Measurement Information - for 3.3V Outpt Load AC Test Circuit diagram corrected GND from "-1.165V±5%" to "-1.65V±5%". | 4/23/04 |
| A | T10 | 11 | Ordering Information Table - added Lead-Free part number. | 10/11/04 |
| B | T7B | 6 | AC Characteristics Table - changed tjit(cc) from 120ps max to 170ps max. | 1/28/05 |
| B | | 1 | Feature section, Cycle-to-Cycle Jitter note - added "@ 3.3V". | 3/11/05 |
| C | T2 | 3 | Pin Characteristics Table - corrected R _{PULLUP/DOWN} values from 51Ω max. to 51kΩ typical. Crystal Characterisitics Table - Added Drive Level parameter. Added <i>Recommendations for Unused Input and Output Pins</i> . Ordering Information Table - added lead-free note. | 11/11/05 |
| | T5 | 6 | | |
| | T10 | 9 12 | | |
| C | T10 | 10 | Added <i>LVC MOS to XTAL Interface</i> . | 4/28/06 |
| | | 12 | Ordering Information Table - corrected lead-free marking. | |
| C | T10 | 13 | Updated datasheet's header/footer with IDT from ICS. | 10/13/10 |
| | | 15 | Removed ICS prefix from Part/Order Number column. Added Contact Page. | |
| C | T10 | 1 | Removed ICS from part number where needed. | 1/25/16 |
| | | 13 | Features section - removed reference to leaded packages. Ordering Information - removed quantity from tape and reel. Deleted LF note below table. Updated header and footer. | |



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